Electronic Patent Application Fee Transmittal							
Application Number:	10	10003180					
Filing Date:	30	30-Oct-2001					
Title of Invention:	EF	SEMICONDUCTOR TEST SYSTEM AND METHOD FOR EFFECTIVELY TESTING A SEMICONDUCTOR DEVICE HAVING MANY PINS					
First Named Inventor:	Не	Heon-Deok Park					
Filer:	Al	Alexander Charles Johnson/Li Mei Vermilya					
Attorney Docket Number:	98	9898-197					
Filed as Large Entity							
Utility Filing Fees							
Description		Fee Code	Quantity	Amount	Sub-Total in USD(\$)		
Basic Filing:					1		
Pages:							
Claims:							
Miscellaneous-Filing:							
Publ. Fee- early, voluntary, or normal		1504	1	300	300		
Petition:							
Patent-Appeals-and-Interference:							
Post-Allowance-and-Post-Issuance:							
Utility Appl issue fee		1501	1	1400	1400		

Description	Fee Code	Quantity	Amount	Sub-Total in USD(\$)
Extension-of-Time:				
Miscellaneous:				
	Total in USD (\$)			1700